

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/025,780 | Applicant(s)/Patent Under Reexamination PARK ET AL. | |
| | Examiner Sonny TRINH | Art Unit 2687 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| * | A | US-6,847,327 | 01-2005 | Ylitalo, Juha | 342/407 |
| * | B | US-6,026,304 | 02-2000 | Hilsenrath et al. | 455/456.2 |
| * | C | US-6,249,680 | 06-2001 | Wax et al. | 455/456.2 |
| * | D | US-2005/0136841 | 06-2005 | Frank, Colin | 455/065 |
| * | E | US-6,600,445 | 07-2003 | Li, Shihe | 342/368 |
| * | F | US-2003/0152099 | 08-2003 | Chun et al. | 370/441 |
| * | G | US-2005/0025223 | 02-2005 | Dabak et al. | 375/147 |
| * | H | US-6,108,565 | 08-2000 | Scherzer, Shimon B. | 455/562.1 |
| * | I | US-2003/0216156 | 11-2003 | Chun, Byung-Jin | 455/562.1 |
| * | J | US-2003/0048760 | 03-2003 | Park et al. | 370/295 |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.